

MOS FIELD EFFECT TRANSISTOR 2SK3575

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The 2SK3575 is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, designed for low voltage high current applications such as DC/DC converter with synchronous rectifier.

FEATURES

- •4.5V drive available
- •Low on-state resistance

RDS(on)1 = $4.5 \text{ m}\Omega$ MAX. (Vgs = 10 V, ID = 42 A)

Low gate charge

 $Q_G = 70 \text{ nC TYP}$. $(V_{DD} = 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 83 \text{ A})$

- Avalanche capability ratings
- •Surface mount device available

★ ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3575	TO-220AB
2SK3575-S	TO-262
2SK3575-ZK	TO-263
2SK3575-Z	TO-220SMD ^{Note}

Note TO-220SMD package is produced only in Japan.

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	30	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	I _{D(DC)}	±83	Α
Drain Current (pulse) Note1	D(pulse)	±332	Α
Total Power Dissipation (T _A = 25°C)	P _{T1}	1.5	W
Total Power Dissipation (Tc = 25°C)	P _{T2}	105	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C
Single Avalanche Current Note2	las	57	Α
Single Avalanche Energy Note2	Eas	325	mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = 15 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V

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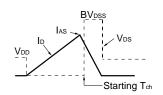


ELECTRICAL CHARACTERISTICS (TA = 25°C)

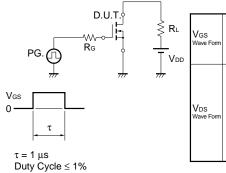
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	Vps = 30 V, Vgs = 0 V			10	μΑ
Gate Leakage Current	Igss	Vgs = ±20 V, Vps = 0 V			±100	nA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5		2.5	٧
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 42 A	27			S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 42 A		3.3	4.5	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 42 A		4.3	6.4	mΩ
Input Capacitance	Ciss	Vps = 10 V		3700		pF
Output Capacitance	Coss	Vgs = 0 V		1430		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		500		pF
Turn-on Delay Time	td(on)	V _{DD} = 15 V, I _D = 42 A		26		ns
Rise Time	tr	Vgs = 10 V		27		ns
Turn-off Delay Time	td(off)	$R_G = 10 \Omega$		110		ns
Fall Time	t _f			40		ns
Total Gate Charge	QG	VDD = 24 V		70		nC
Gate to Source Charge	Qgs	Vgs = 10 V		12		nC
Gate to Drain Charge	Q _{GD}	ID = 83 A		20		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 83 A, VGS = 0 V		1.0		٧
Reverse Recovery Time	trr	IF = 83 A, VGS = 0 V		61		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		94		nC

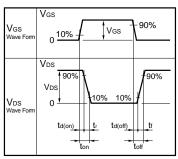
★ TEST CIRCUIT 1 AVALANCHE CAPABILITY

$V_{GS} = 20 \rightarrow 0 \text{ V}$



TEST CIRCUIT 2 SWITCHING TIME

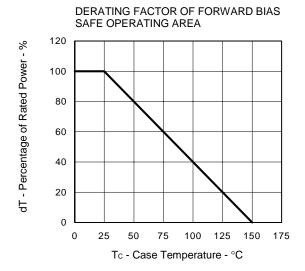


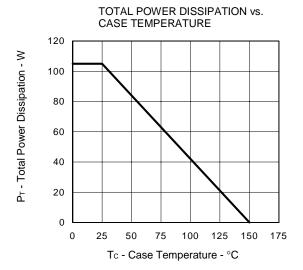


TEST CIRCUIT 3 GATE CHARGE

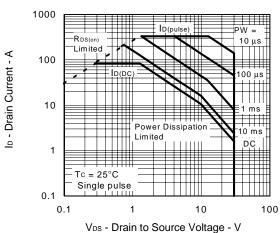


TYPICAL CHARACTERISTICS (TA = 25°C)

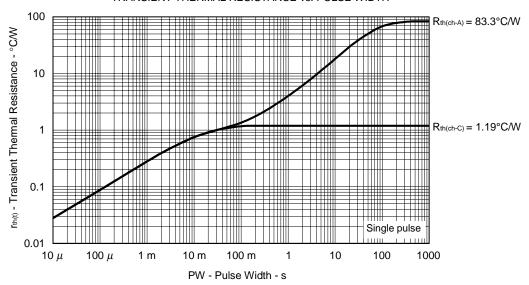




FORWARD BIAS SAFE OPERATING AREA







3



0

0

DRAIN TO SOURCE VOLTAGE

350
300
250
VGS = 10 V
4.5 V

0.5

1

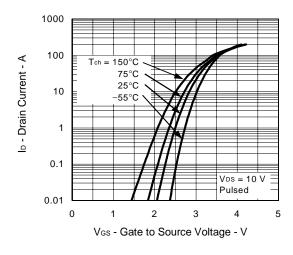
V_{DS} - Drain to Source Voltage - V

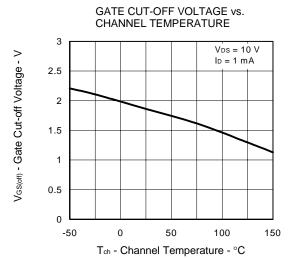
1.5

2

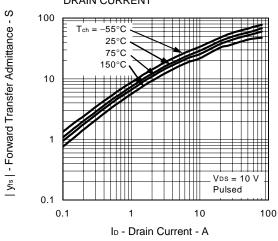
DRAIN CURRENT vs.

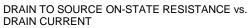
FORWARD TRANSFER CHARACTERISTICS

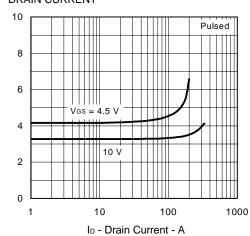




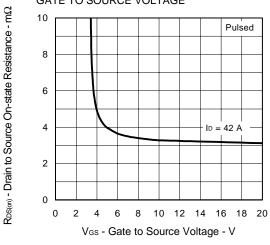
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT







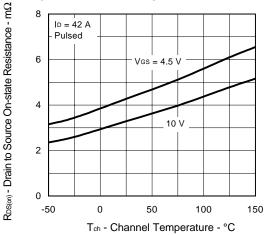
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



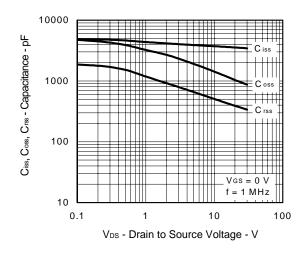
R_{DS(m)} - Drain to Source On-state Resistance - mΩ



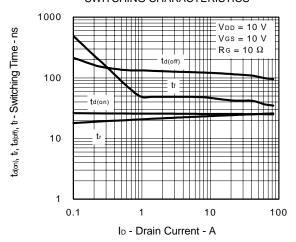
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



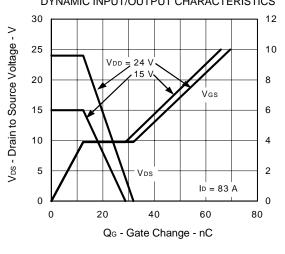
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



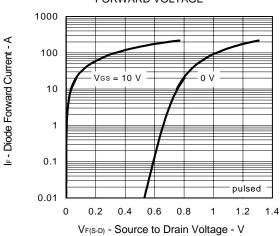
SWITCHING CHARACTERISTICS



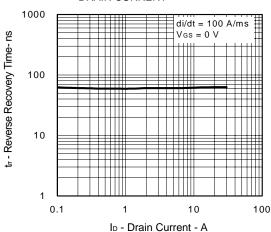
DYNAMIC INPUT/OUTPUT CHARACTERISTICS

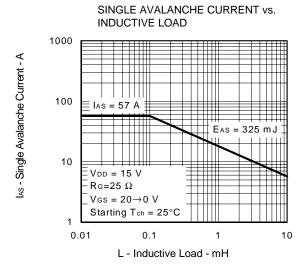


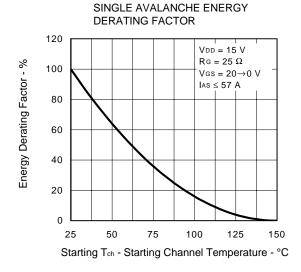
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



REVERSE RECOVERY TIME vs. DRAIN CURRENT



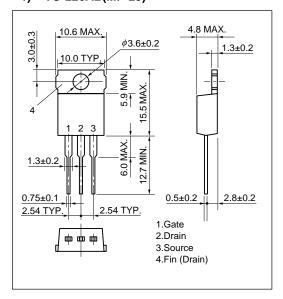




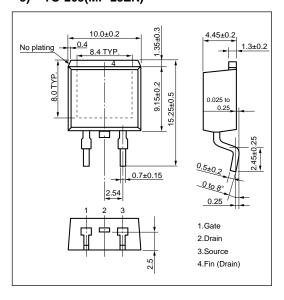


★ PACKAGE DRAWINGS (Unit: mm)

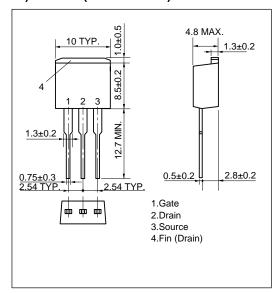
1) TO-220AB(MP-25)



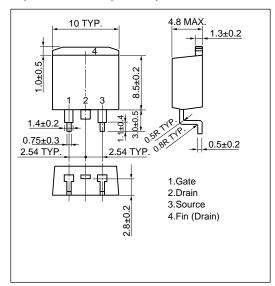
3) TO-263(MP-25ZK)



2) TO-262(MP-25 Fin Cut)

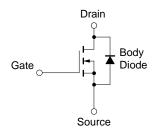


4) TO-220SMD(MP-25Z)^{Note}



Note This package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

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